Freescale Semiconductor

Data Sheet: Technical Data

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MCF5271 Integrated Microprocessor Hardware Specification

by: Microcontroller Solutions Group

The MCF5271 family is a highly integrated implementation of the ColdFire[®] family of reduced instruction set computing (RISC) microprocessors. This document describes pertinent features and functions of the MCF5271 family. The MCF5271 family includes the MCF5271 and MCF5270 microprocessors. The differences between these parts are summarized below in Table 1. This document is written from the perspective of the MCF5271 and unless otherwise noted, the information applies also to the MCF5270.

The MCF5271 family combines low cost with high integration on the popular version 2 ColdFire core with over 144 (Dhrystone 2.1) MIPS at 150 MHz. Positioned for applications requiring a cost-sensitive 32-bit solution, the MCF5271 family features a 10/100 Ethernet MAC and optional hardware encryption to ensure the application can be connected and protected. In addition, the MCF5271 family features an enhanced multiply accumulate unit (eMAC), large on-chip memory (64 Kbytes SRAM, 8 Kbytes configurable cache), and a 32-bit SDR SDRAM memory controller.

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1 MCF5271 Family Configurations

| Module | MCF5270 | MCF5271 |
|--|------------------------|------------------------|
| ColdFire V2 Core with EMAC and Hardware Divide | х | x |
| System Clock | 150 | MHz |
| Performance (Dhrystone/2.1 MIPS) | 14 | 14 |
| Instruction/Data Cache | 8 Kt | oytes |
| Static RAM (SRAM) | 64 K | bytes |
| Interrupt Controllers (INTC) | 2 | 2 |
| Edge Port Module (EPORT) | х | х |
| External Interface Module (EIM) | х | х |
| 4-channel Direct-Memory Access (DMA) | х | х |
| SDRAM Controller | х | х |
| Fast Ethernet Controller (FEC) | х | х |
| Hardware Encryption | — | х |
| Watchdog Timer (WDT) | х | х |
| Four Periodic Interrupt Timers (PIT) | х | х |
| 32-bit DMA Timers | 4 | 4 |
| QSPI | х | х |
| UART(s) | 3 | 3 |
| l ² C | х | х |
| General Purpose I/O Module (GPIO) | х | х |
| JTAG - IEEE 1149.1 Test Access Port | х | х |
| Package | 160 QFP, 196 MAPBGA | 160 QFP, 196 MAPBGA |

Table 1. MCF5271 Family Configurations

2 Block Diagram

The superset device in the MCF5271 family comes in a 196 mold array plastic ball grid array (MAPBGA) package. Figure 1 shows a top-level block diagram of the MCF5271.

Block Diagram

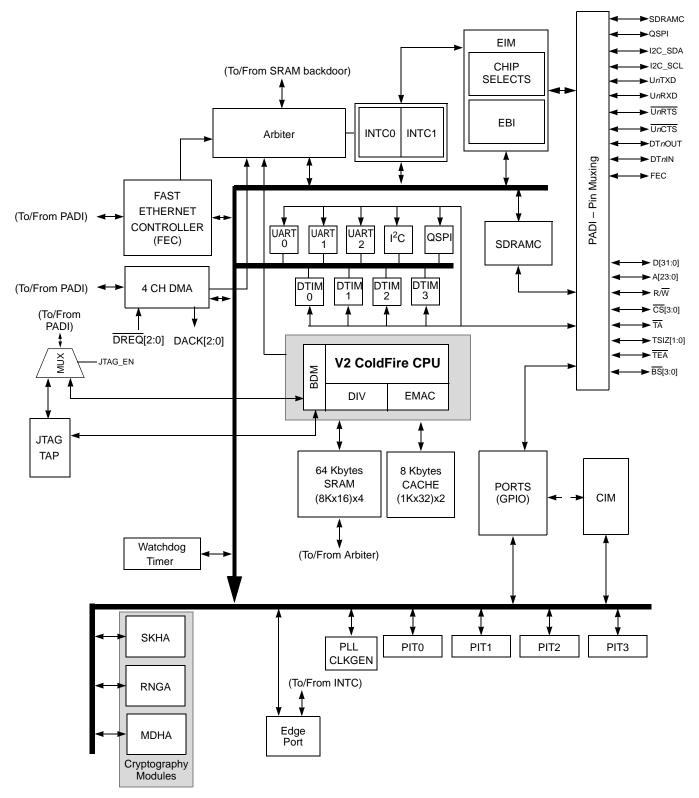


Figure 1. MCF5271 Block Diagram

Features

3 Features

For a detailed feature list see the MCF5271 Reference Manual (MCF5271RM).

4 Signal Descriptions

This section describes signals that connect off chip, including a table of signal properties. For a more detailed discussion of the MCF5271 signals, consult the *MCF5271 Reference Manual* (MCF5271RM).

4.1 Signal Properties

Table 4 lists all of the signals grouped by function. The "Dir" column is the direction for the primary function of the pin. Refer to Section 6, "Mechanicals/Pinouts and Part Numbers," for package diagrams.

NOTE

In this table and throughout this document a single signal within a group is designated without square brackets (i.e., A24), while designations for multiple signals within a group use brackets (i.e., A[23:21]) and is meant to include all signals within the two bracketed numbers when these numbers are separated by a colon.

NOTE

The primary functionality of a pin is not necessarily its default functionality. Pins that are muxed with GPIO will default to their GPIO functionality.

| Signal Name | Name GPIO Alternate 1 | | Alternate 2 | Dir. ¹ | MCF5270 MCF5271 160 QFP | MCF5270 MCF5271 196 MAPBGA | | | |
|--|-----------------------|--------------|---------------|-------------------|-------------------------------|----------------------------------|--|--|--|
| Reset | | | | | | | | | |
| RESET — — — I 83 N13 | | | | | | | | | |
| RSTOUT | _ | _ | | 0 | 82 | P13 | | | |
| Clock | | | | | | | | | |
| EXTAL | _ | — | _ | I | 86 | M14 | | | |
| XTAL | _ | _ | _ | 0 | 85 | N14 | | | |
| CLKOUT | _ | _ | _ | 0 | 89 | K14 | | | |
| | | Мс | de Selection | n | | | | | |
| CLKMOD[1:0] | _ | — | _ | I | 20,21 | G5,H5 | | | |
| RCON | _ | — | _ | Ι | 79 | K10 | | | |
| | E | External Mem | nory Interfac | e and | Ports | | | | |
| A[23:21] | PADDR[7:5] | CS[6:4] | | 0 | 126, 125, 124 | B11, C11, D11 | | | |

Table 2. MCF5270 and MCF5271 Signal Information and Muxing

| Signal Name | GPIO | Alternate 1 | Alternate 2 | Dir. ¹ | MCF5270 MCF5271 160 QFP | MCF5270 MCF5271 196 MAPBGA | | | | |
|------------------|-------------|-------------|-------------|-------------------|-------------------------------|---|--|--|--|--|
| A[20:0] | _ | _ | _ | 0 | 123:115, 112:106, 102:98 | A12, B12, C12, A13, B13, B14, C13, C14, D12, D13, D14, E11, E12, E13, E14, F12, F13, F14, G11, G12, G13 | | | | |
| D[31:16] | _ | _ | _ | 0 | 22:30, 33:39 | G1, G2, H1, H2, H3, H4, J1, J2, J3, J4, K1, K2, K3, K4, L1, L2 | | | | |
| D[15:8] | PDATAH[7:0] | _ | _ | 0 | 42:49 | M1, N1, M2, N2, P2, L3, M3, N3 | | | | |
| D[7:0] | PDATAL[7:0] | — | _ | 0 | 50:52, 56:60 | P3, M4, N4, P4, L5, M5, N5, P5 | | | | |
| BS[3:0] | PBS[7:4] | CAS[3:0] | | 0 | 143:140 | B6, C6, D7, C7 | | | | |
| OE | PBUSCTL7 | — | | 0 | 62 | N6 | | | | |
| TA | PBUSCTL6 | _ | | Ι | 96 | H11 | | | | |
| TEA | PBUSCTL5 | DREQ1 | _ | Ι | — | J14 | | | | |
| R/W | PBUSCTL4 | — | _ | 0 | 95 | J13 | | | | |
| TSIZ1 | PBUSCTL3 | DACK1 | | 0 | | P6 | | | | |
| TSIZ0 | PBUSCTL2 | DACK0 | | 0 | | P7 | | | | |
| TS | PBUSCTL1 | DACK2 | | 0 | 97 | H13 | | | | |
| TIP | PBUSCTL0 | DREQ0 | | 0 | | H12 | | | | |
| | | C | hip Selects | | | | | | | |
| <u>CS</u> [7:4] | PCS[7:4] | _ | _ | 0 | _ | B9, A10, C10, A11 | | | | |
| <u>CS</u> [3:2] | PCS[3:2] | SD_CS[1:0] | _ | 0 | 132,131 | A9, C9 | | | | |
| CS1 | PCS1 | | | 0 | 130 | B10 | | | | |
| CS0 | — | | — | 0 | 129 | D10 | | | | |
| SDRAM Controller | | | | | | | | | | |
| SD_WE | PSDRAM5 | — | — | 0 | 92 | K13 | | | | |
| SD_SCAS | PSDRAM4 | — | — | 0 | 91 | K12 | | | | |
| SD_SRAS | PSDRAM3 | — | — | 0 | 90 | K11 | | | | |
| SD_CKE | PSDRAM2 | — | _ | 0 | _ | E8 | | | | |
| SD_CS[1:0] | PSDRAM[1:0] | — | _ | 0 | _ | L12, L13 | | | | |

Table 2. MCF5270 and MCF5271 Signal Information and Muxing (continued)

Signal Descriptions

| Signal Name | GPIO | Alternate 1 | Alternate 2 | Dir. ¹ | MCF5270 MCF5271 160 QFP | MCF5270 MCF5271 196 MAPBGA | | | |
|--|--|-------------|------------------|-------------------|-------------------------------|----------------------------------|--|--|--|
| External Interrupts Port | | | | | | | | | |
| IRQ[7:3] | PIRQ[7:3] | — | — | Ι | IRQ7=63 IRQ4=64 | N7, M7, L7, P8, N8 | | | |
| IRQ2 | PIRQ2 | DREQ2 | — | Ι | — | M8 | | | |
| IRQ1 | PIRQ1 | — | | Ι | 65 | L8 | | | |
| | | | FEC | | | | | | |
| EMDC | PFECI2C3 | I2C_SCL | U2TXD | 0 | 151 | D4 | | | |
| EMDIO | PFECI2C2 | I2C_SDA | U2RXD | I/O | 150 | D5 | | | |
| ECOL | | _ | _ | Ι | 9 | E2 | | | |
| ECRS | | _ | _ | Ι | 8 | E1 | | | |
| ERXCLK | _ | _ | _ | Ι | 7 | D1 | | | |
| ERXDV | | | _ | Ι | 6 | D2 | | | |
| ERXD[3:0] | | — | _ | Ι | 5:2 | D3, C1, C2, B1 | | | |
| ERXER | | — | | 0 | 159 | B2 | | | |
| ETXCLK | | | | | 158 | A2 | | | |
| ETXEN | _ | — | — | Ι | 157 | C3 | | | |
| ETXER | | — | — | 0 | 156 | B3 | | | |
| ETXD[3:0] | _ | — | — | 0 | 155:152 | A3, A4, C4, B4 | | | |
| | | | l ² C | | | | | | |
| I2C_SDA | PFECI2C1 | — | — | I/O | _ | J12 | | | |
| I2C_SCL | PFECI2C0 | — | — | I/O | — | J11 | | | |
| | | • | DMA | | | | | | |
| pads. Ple TS and DT2OL TSIZ0 and DT0 | DACK[2:0] and DREQ[2:0] do not have a dedicated bond — — — — — — — — — — — — — — — — — — — | | | | | | | | |
| QSPI | | | | | | | | | |
| QSPI_CS1 | PQSPI4 | SD_CKE | _ | 0 | 139 | B7 | | | |
| QSPI_CS0 | PQSPI3 | — | _ | 0 | 146 | A6 | | | |
| QSPI_CLK | PQSPI2 | I2C_SCL | | 0 | 147 | C5 | | | |
| QSPI_DIN | PQSPI1 | I2C_SDA | | Ι | 148 | B5 | | | |
| QSPI_DOUT | PQSPI0 | — | — | 0 | 149 | A5 | | | |

Table 2. MCF5270 and MCF5271 Signal Information and Muxing (continued)

| Signal Name | GPIO | Alternate 1 | Alternate 2 | Dir. ¹ | MCF5270 MCF5271 160 QFP | MCF5270 MCF5271 196 MAPBGA |
|-------------|---------|-------------|-----------------------|-------------------|-------------------------------|----------------------------------|
| | | 1 | UARTs | | | |
| U2TXD | PUARTH1 | | _ | 0 | _ | A8 |
| U2RXD | PUARTH0 | — | — | Ι | _ | A7 |
| U1CTS | PUARTL7 | U2CTS | — | Ι | 136 | B8 |
| U1RTS | PUARTL6 | U2RTS | — | 0 | 135 | C8 |
| U1TXD | PUARTL5 | — | — | 0 | 133 | D9 |
| U1RXD | PUARTL4 | — | — | Ι | 134 | D8 |
| UOCTS | PUARTL3 | — | _ | Ι | 12 | F3 |
| UORTS | PUARTL2 | — | — | 0 | 15 | G3 |
| U0TXD | PUARTL1 | — | — | 0 | 14 | F1 |
| U0RXD | PUARTL0 | — | | Ι | 13 | F2 |
| | | C | MA Timers | | | 4 |
| DT3IN | PTIMER7 | U2CTS | QSPI_CS2 | Ι | | H14 |
| DT3OUT | PTIMER6 | U2RTS | QSPI_CS3 | 0 | _ | G14 |
| DT2IN | PTIMER5 | DREQ2 | DT2OUT | Ι | 66 | M9 |
| DT2OUT | PTIMER4 | DACK2 | — | 0 | — | L9 |
| DT1IN | PTIMER3 | DREQ1 | DT1OUT | Ι | 61 | L6 |
| DT1OUT | PTIMER2 | DACK1 | — | 0 | — | M6 |
| DT0IN | PTIMER1 | DREQ0 | — | Ι | 10 | E4 |
| DT0OUT | PTIMER0 | DACK0 | — | 0 | 11 | F4 |
| | | Ē | BDM/JTAG ² | | | |
| DSCLK | _ | TRST | _ | 0 | 70 | N9 |
| PSTCLK | _ | TCLK | _ | 0 | 68 | P9 |
| BKPT | _ | TMS | — | 0 | 71 | P10 |
| DSI | | TDI | — | Ι | 73 | M10 |
| DSO | | TDO | — | 0 | 72 | N10 |
| JTAG_EN | _ | — | — | Ι | 78 | K9 |
| DDATA[3:0] | _ | — | — | 0 | _ | M12, N12, P12 L11 |
| PST[3:0] | _ | — | — | 0 | 77:74 | M11, N11, P11 L10 |

Table 2. MCF5270 and MCF5271 Signal Information and Muxing (continued)

Design Recommendations

| Signal Name GPIO Alternate 1 | | Alternate 2 | Dir. ¹ | MCF5270 MCF5271 160 QFP | MCF5270 MCF5271 196 MAPBGA | | | | | |
|------------------------------|---|-------------|-------------------|-------------------------------|---|--|--|--|--|--|
| Test | | | | | | | | | | |
| TEST — — I 19 F5 | | | | | | | | | | |
| PLL_TEST | _ | — | _ | I | — | | | | | |
| | | Po | wer Supplie | s | | | | | | |
| VDDPLL — | | | | I | 87 | M13 | | | | |
| VSSPLL — | | — | _ | I | 84 | L14 | | | | |
| OVDD | _ | _ | _ | I | 1, 18, 32, 41, 55, 69, 81, 94, 105, 114, 128, 138, 145 | E5, E7, E10, F7, F9, G6, G8, H7, H8, H9, J6, J8, J10, K5, K6, K8 | | | | |
| VSS | _ | _ | _ | I | 17, 31, 40, 54, 67, 80, 88, 93, 104, 113, 127, 137, 144, 160 | A1, A14, E6, E9, F6, F8, F10, G7, G9, H6, J5, J7, J9, K7, P1, P14 | | | | |
| VDD | | | | I | 16, 53, 103 | D6, F11, G4, L4 | | | | |

 Table 2. MCF5270 and MCF5271 Signal Information and Muxing (continued)

¹ Refers to pin's primary function. All pins which are configurable for GPIO have a pullup enabled in GPIO mode with the exception of PBUSCTL[7], PBUSCTL[4:0], PADDR, PBS, PSDRAM.

² If JTAG_EN is asserted, these pins default to Alternate 1 (JTAG) functionality. The GPIO module is not responsible for assigning these pins.

5 Design Recommendations

5.1 Layout

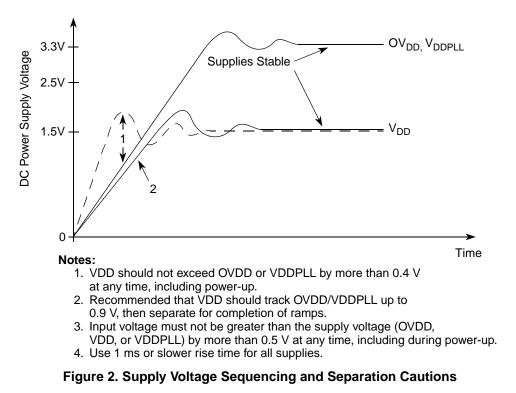
- Use a 4-layer printed circuit board with the VDD and GND pins connected directly to the power and ground planes for the MCF5271.
- See application note AN1259, System Design and Layout Techniques for Noise Reduction in Processor-Based Systems.
- Match the PC layout trace width and routing to match trace length to operating frequency and board impedance. Add termination (series or therein) to the traces to dampen reflections. Increase the PCB impedance (if possible) keeping the trace lengths balanced and short. Then do cross-talk analysis to separate traces with significant parallelism or are otherwise "noisy". Use 6 mils trace and separation. Clocks get extra separation and more precise balancing.

5.2 Power Supply

• 33 μ F, 0.1 μ F, and 0.01 μ F across each power supply

5.2.1 Supply Voltage Sequencing and Separation Cautions

Figure 2 shows situations in sequencing the I/O V_{DD} (OV_{DD}), PLL V_{DD} (V_{DDPLL}), and Core V_{DD} (V_{DD}). OV_{DD} is specified relative to V_{DD} .



5.2.1.1 Power Up Sequence

If OV_{DD} is powered up with V_{DD} at 0 V, then the sense circuits in the I/O pads cause all pad output drivers connected to the OV_{DD} to be in a high impedance state. There is no limit on how long after OV_{DD} powers up before V_{DD} must power up. V_{DD} should not lead the OV_{DD} or V_{DDPLL} by more than 0.4 V during power ramp-up, or there will be high current in the internal ESD protection diodes. The rise times on the power supplies should be slower than 1 μ s to avoid turning on the internal ESD protection clamp diodes.

The recommended power up sequence is as follows:

- 1. Use 1 ms or slower rise time for all supplies.
- 2. V_{DD} and OV_{DD}/V_{DDPLL} should track up to 0.9 V, then separate for the completion of ramps with OV_{DD} going to the higher external voltages. One way to accomplish this is to use a low drop-out voltage regulator.

5.2.1.2 Power Down Sequence

If V_{DD} is powered down first, then sense circuits in the I/O pads cause all output drivers to be in a high impedance state. There is no limit on how long after V_{DD} powers down before OV_{DD}/V_{DDPLL} must power down. V_{DD} should not lag OV_{DD} or V_{DDPLL} going low by more than 0.4 V during power down or there

Design Recommendations

will be undesired high current in the ESD protection diodes. There are no requirements for the fall times of the power supplies.

The recommended power down sequence is as follows:

- 1. Drop V_{DD} to 0 V.
- 2. Drop OV_{DD}/V_{DDPLL} supplies.

5.3 Decoupling

- Place the decoupling caps as close to the pins as possible, but they can be outside the footprint of the package.
- 0.1 μ F and 0.01 μ F at each supply input

5.4 Buffering

• Use bus buffers on all data/address lines for all off-board accesses and for all on-board accesses when excessive loading is expected. See Section 7, "Electrical Characteristics."

5.5 Pull-up Recommendations

• Use external pull-up resistors on unused inputs. See pin table.

5.6 Clocking Recommendations

- Use a multi-layer board with a separate ground plane.
- Place the crystal and all other associated components as close to the EXTAL and XTAL (oscillator pins) as possible.
- Do not run a high frequency trace around crystal circuit.
- Ensure that the ground for the bypass capacitors is connected to a solid ground trace.
- Tie the ground trace to the ground pin nearest EXTAL and XTAL. This prevents large loop currents in the vicinity of the crystal.
- Tie the ground pin to the most solid ground in the system.
- Do not connect the trace that connects the oscillator and the ground plane to any other circuit element. This tends to make the oscillator unstable.
- Tie XTAL to ground when an external oscillator is clocking the device.

5.7 Interface Recommendations

5.7.1 SDRAM Controller

5.7.1.1 SDRAM Controller Signals in Synchronous Mode

Table 3 shows the behavior of SDRAM signals in synchronous mode.

| Signal | Description |
|------------|--|
| SD_SRAS | Synchronous row address strobe. Indicates a valid SDRAM row address is present and can be latched by the SDRAM. SD_SRAS should be connected to the corresponding SDRAM SD_SRAS. Do not confuse SD_SRAS with the DRAM controller's SD_CS[1:0], which should not be interfaced to the SDRAM SD_SRAS signals. |
| SD_SCAS | Synchronous column address strobe. Indicates a valid column address is present and can be latched by the SDRAM. SD_SCAS should be connected to the corresponding signal labeled SD_SCAS on the SDRAM. |
| DRAMW | DRAM read/write. Asserted for write operations and negated for read operations. |
| SD_CS[1:0] | Row address strobe. Select each memory block of SDRAMs connected to the MCF5271. One SD_CS signal selects one SDRAM block and connects to the corresponding \overline{CS} signals. |
| SD_CKE | Synchronous DRAM clock enable. Connected directly to the CKE (clock enable) signal of SDRAMs. Enables and disables the clock internal to SDRAM. When CKE is low, memory can enter a power-down mode where operations are suspended or they can enter self-refresh mode. SD_CKE functionality is controlled by DCR[COC]. For designs using external multiplexing, setting COC allows SD_CKE to provide command-bit functionality. |
| BS[3:0] | Column address strobe. For synchronous operation, $\overline{\text{BS}}$ [3:0] function as byte enables to the SDRAMs. They connect to the DQM signals (or mask qualifiers) of the SDRAMs. |
| CLKOUT | Bus clock output. Connects to the CLK input of SDRAMs. |

Table 3. Synchronous DRAM Signal Connections

5.7.1.2 Address Multiplexing

See the SDRAM controller module chapter in the *MCF5271 Reference Manual* for details on address multiplexing.

5.7.2 Ethernet PHY Transceiver Connection

The FEC supports both an MII interface for 10/100 Mbps Ethernet and a seven-wire serial interface for 10 Mbps Ethernet. The interface mode is selected by R_CNTRL[MII_MODE]. In MII mode, the 802.3 standard defines and the FEC module supports 18 signals. These are shown in Table 4.

| Signal Description | MCF5271 Pin |
|--------------------|-------------|
| Transmit clock | ETXCLK |
| Transmit enable | ETXEN |
| Transmit data | ETXD[3:0] |
| Transmit error | ETXER |
| Collision | ECOL |
| Carrier sense | ECRS |
| Receive clock | ERXCLK |
| Receive enable | ERXDV |
| Receive data | ERXD[3:0] |

Table 4. MII Mode

Mechanicals/Pinouts and Part Numbers

| Signal Description | MCF5271 Pin | | | |
|--------------------------------|-------------|--|--|--|
| Receive error | ERXER | | | |
| Management channel clock | EMDC | | | |
| Management channel serial data | EMDIO | | | |

Table 4. MII Mode (continued)

The serial mode interface operates in what is generally referred to as AMD mode. The MCF5271 configuration for seven-wire serial mode connections to the external transceiver are shown in Table 5.

| Signal Description | MCF5271 Pin |
|--------------------------------------|-------------|
| Transmit clock | ETXCLK |
| Transmit enable | ETXEN |
| Transmit data | ETXD[0] |
| Collision | ECOL |
| Receive clock | ERXCLK |
| Receive enable | ERXDV |
| Receive data | ERXD[0] |
| Unused, configure as PB14 | ERXER |
| Unused input, tie to ground | ECRS |
| Unused, configure as PB[13:11] | ERXD[3:1] |
| Unused output, ignore | ETXER |
| Unused, configure as PB[10:8] | ETXD[3:1] |
| Unused, configure as PB15 | EMDC |
| Input after reset, connect to ground | EMDIO |

Table 5. Seven-Wire Mode Configuration

Refer to the M5271EVB evaluation board user's manual for an example of how to connect an external PHY. Schematics for this board are accessible at the MCF5271 site by navigating to: http://www.freescale.com/coldfire.

5.7.3 BDM

Use the BDM interface as shown in the M5271EVB evaluation board user's manual. The schematics for this board are accessible at the Freescale website at: http://www.freescale.com/coldfire.

6 Mechanicals/Pinouts and Part Numbers

This section contains drawings showing the pinout and the packaging and mechanical characteristics of the MCF5271 devices. See Table 4 for a list the signal names and pin locations for each device.

6.1 Pinout—196 MAPBGA

The following figure shows a pinout of the MCF5270/71CVMxxx package.

| | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 9 | 10 | 11 | 12 | 13 | 14 | |
|---|--------|--------|-------|---------------|---------------|---------------|----------|--------|-----------------|--------------|---------------|---------|--------|--------|---|
| A | | ETXCLK | ETXD3 | ETXD2 | QSPI_ DOUT | QSPI_CS0 | U2RXD | U2TXD | CS3 | CS6 | CS4 | A20 | A17 | | А |
| в | ERXD0 | ERXER | ETXER | ETXD0 | QSPI_DIN | BS3 | QSPI_CS1 | U1CTS | CS7 | CS1 | A23 | A19 | A16 | A15 | в |
| С | ERXD2 | ERXD1 | ETXEN | ETXD1 | QSCK | BS2 | BSO | RTS1 | CS2 | CS5 | A22 | A18 | A14 | A13 | с |
| D | ERXCLK | ERXDV | ERXD3 | EMDC | EMDIO | Core VDD_4 | BS1 | U1RXD1 | U1TXD | CS0 | A21 | A12 | A11 | A10 | D |
| E | ECRS | ECOL | NC | TINO | VDD | VSS | VDD | SD_CKE | VSS | VDD | A9 | A8 | A7 | A6 | E |
| F | U0TXD | U0RXD | U0CTS | DTOUT0 | TEST | | VDD | VSS | VDD | VSS | Core VDD_3 | A5 | A4 | A3 | F |
| G | D31 | D30 | UORTS | Core VDD_1 | CLK MOD1 | VDD | VSS | VDD | VSS | NC | A2 | A1 | A0 | DTOUT3 | G |
| н | D29 | D28 | D27 | D26 | CLK MOD0 | VSS | VDD | VDD | VDD | NC | TA | TIP | TS | DTIN3 | н |
| J | D25 | D24 | D23 | D22 | VSS | VDD | VSS | VDD | VSS | VDD | I2C_SCL | I2C_SDA | R/W | TEA | J |
| к | D21 | D20 | D19 | D18 | VDD | VDD | | VDD | JTAG_EN | RCON | SD_RAS | SD_CAS | SD_WE | CLKOUT | к |
| L | D17 | D16 | D10 | Core VDD_2 | D3 | DTIN1 | IRQ5 | IRQ1 | DTOUT2 | PST0 | DDATA0 | SD_CS1 | SD_CS0 | VSSPLL | L |
| М | D15 | D13 | D9 | D6 | D2 | DTOUT1 | IRQ6 | IRQ2 | DTIN2 | TDI/DSI | PST3 | DDATA3 | VDDPLL | EXTAL | м |
| N | D14 | D12 | D8 | D5 | D1 | OE | IRQ7 | IRQ3 | TRST/ DSCLK | TDO/DSO | PST2 | DDATA2 | RESET | XTAL | N |
| Ρ | VSS | D11 | D7 | D4 | D0 | TSIZ1 | TSIZ0 | IRQ4 | TCLK/ PSTCLK | TMS/ BKPT | PST1 | DDATA1 | RSTOUT | VSS | Р |
| - | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 9 | 10 | 11 | 12 | 13 | 14 | 1 |

Figure 3. MCF5270/71CVMxxx Pinout (196 MAPBGA)

Mechanicals/Pinouts and Part Numbers

6.2 Package Dimensions—196 MAPBGA

Figure 4 shows MCF5270/71CVMxxx package dimensions.

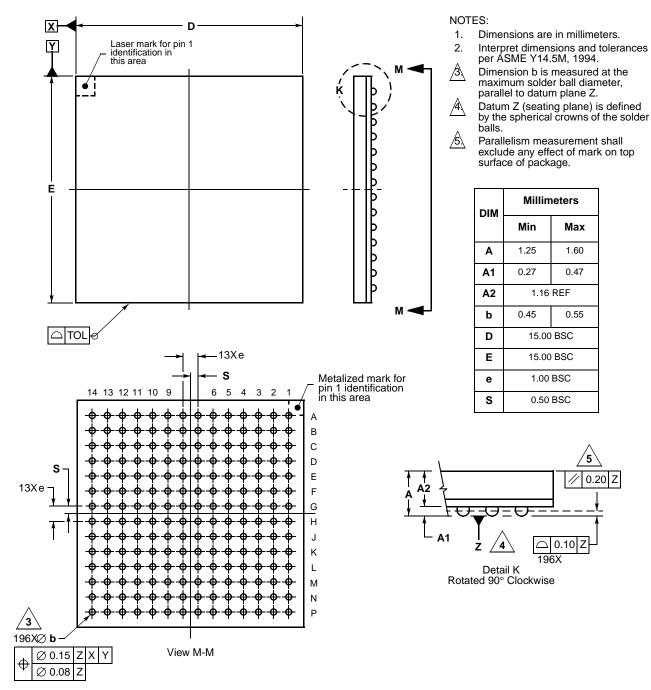


Figure 4. 196 MAPBGA Package Dimensions (Case No. 1128A-01)

6.3 Pinout—160 QFP

Figure 5 shows a pinout of the MCF5271CABxxx package.

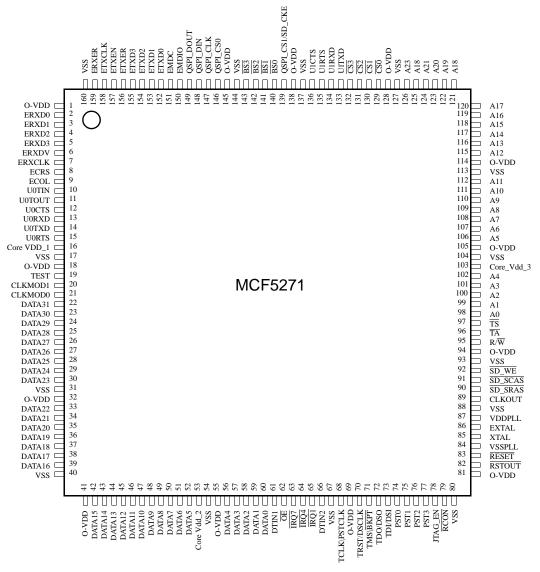


Figure 5. MCF5270/71CABxxx Pinout (160 QFP)

Mechanicals/Pinouts and Part Numbers

6.4 Package Dimensions—160 QFP

Figure 6 shows MCF5270/71CAB80 package dimensions.

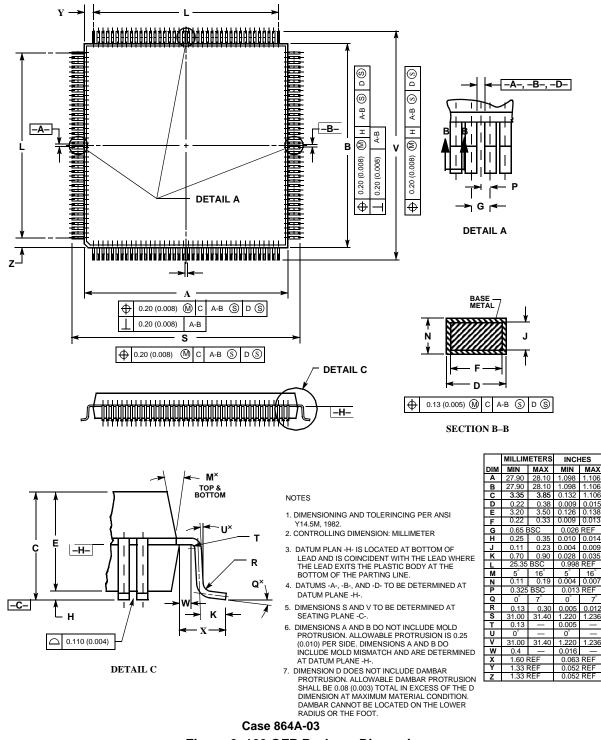


Figure 6. 160 QFP Package Dimensions

6.5 Ordering Information

Table 6. Orderable Part Numbers

| Freescale Part Number | Description | Package | Speed | Lead-Free? | Temperature |
|--------------------------|-----------------------------|------------|--------|------------|----------------|
| MCF5270AB100 | MCF5270 RISC Microprocessor | 160 QFP | 100MHz | Yes | 0° to +70° C |
| MCF5270CAB100 | MCF5270 RISC Microprocessor | 160 QFP | 100MHz | Yes | -40° to +85° C |
| MCF5270VM100 | MCF5270 RISC Microprocessor | 196 MAPBGA | 100MHz | Yes | 0° to +70° C |
| MCF5270CVM150 | MCF5270 RISC Microprocessor | 196 MAPBGA | 150MHz | Yes | -40° to +85° C |
| MCF5271CAB100 | MCF5271 RISC Microprocessor | 160 QFP | 100MHz | Yes | -40° to +85° C |
| MCF5271CVM100 | MCF5271 RISC Microprocessor | 196 MAPBGA | 100MHz | Yes | -40° to +85° C |
| MCF5271CVM150 | MCF5271 RISC Microprocessor | 196 MAPBGA | 150MHz | Yes | -40° to +85° C |

7 Electrical Characteristics

This chapter contains electrical specification tables and reference timing diagrams for the MCF5271 microcontroller unit. This section contains detailed information on power considerations, DC/AC electrical characteristics, and AC timing specifications of MCF5271.

NOTE

The parameters specified in this processor document supersede any values found in the module specifications.

7.1 Maximum Ratings

 Table 7. Absolute Maximum Ratings^{1, 2}

| Rating | Symbol | Value | Unit | | | |
|--|--|----------------|------|--|--|--|
| Core Supply Voltage | V _{DD} | - 0.5 to +2.0 | V | | | |
| Pad Supply Voltage | OV _{DD} | - 0.3 to +4.0 | V | | | |
| PLL Supply Voltage | V _{DDPLL} | - 0.3 to +4.0 | V | | | |
| Digital Input Voltage ³ | V _{IN} | – 0.3 to + 4.0 | V | | | |
| Instantaneous Maximum Current Single pin limit (applies to all pins) ^{3,4,5} | ۱ _D | 25 | mA | | | |
| Operating Temperature Range (Packaged) | T _A (T _L - T _H) | – 40 to 85 | °C | | | |
| Storage Temperature Range | T _{stg} | – 65 to 150 | °C | | | |
| ¹ Functional operating conditions are given in DC Electrical Specifications. Absolute Maximum | | | | | | |

Functional operating conditions are given in DC Electrical Specifications. Absolute Maximum Ratings are stress ratings only, and functional operation at the maxima is not guaranteed. Continued operation at these levels may affect device reliability or cause permanent damage to the device.

- ² This device contains circuitry protecting against damage due to high static voltage or electrical fields; however, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (e.g., either V_{SS} or OV_{DD}).
- ³ Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive and negative clamp voltages, then use the larger of the two values.
- ⁴ All functional non-supply pins are internally clamped to V_{SS} and OV_{DD}.
- ⁵ Power supply must maintain regulation within operating OV_{DD} range during instantaneous and operating maximum current conditions. If positive injection current ($V_{in} > OV_{DD}$) is greater than I_{DD} , the injection current may flow out of OV_{DD} and could result in external power supply going out of regulation. Insure external OV_{DD} load will shunt current greater than maximum injection current. This will be the greatest risk when the processor is not consuming power (ex; no clock).Power supply must maintain regulation within operating OV_{DD} range during instantaneous and operating maximum current conditions.

7.2 Thermal Characteristics

The below table lists thermal resistance values.

| Characteristic | | Symbol | 196 MAPBGA | 160QFP | Unit |
|---|-------------------------|------------------|-------------------|-------------------|------|
| Junction to ambient, natural convection | Four layer board (2s2p) | θ _{JMA} | 32 ^{1,2} | 40 ^{1,2} | °C/W |
| Junction to ambient (@200 ft/min) | Four layer board (2s2p) | θ_{JMA} | 29 ^{1,2} | 36 ^{1,2} | °C/W |
| Junction to board | | θ_{JB} | 20 ³ | 25 ³ | °C/W |
| Junction to case | | θ_{JC} | 10 ⁴ | 10 ⁴ | °C/W |
| Junction to top of package | | Ψ _{jt} | 2 ^{1,5} | 2 ^{1,5} | °C/W |
| Maximum operating junction temperature | | Тj | 104 | 105 | °C |

Table 8. Thermal Characteristics

 θ_{JMA} and Ψ_{jt} parameters are simulated in conformance with EIA/JESD Standard 51-2 for natural convection. Motorola recommends the use of θ_{JmA} and power dissipation specifications in the system design to prevent device junction temperatures from exceeding the rated specification. System designers should be aware that device junction temperatures can be significantly influenced by board layout and surrounding devices. Conformance to the device junction temperature specification can be verified by physical measurement in the customer's system using the Ψ_{jt} parameter, the device power dissipation, and the method described in EIA/JESD Standard 51-2.

- ² Per JEDEC JESD51-6 with the board horizontal.
- ³ Thermal resistance between the die and the printed circuit board in conformance with JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
- ⁴ Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
- ⁵ Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written in conformance with Psi-JT.

The average chip-junction temperature (T_J) in °C can be obtained from:

$$\Gamma_{J} = T_{A} + (P_{D} \times \Theta_{JMA}) (1)$$

Where:

 T_A = Ambient Temperature, °C

 Θ_{IMA} = Package Thermal Resistance, Junction-to-Ambient, °C/W

 $P_D = P_{INT} + P_{I/O}$

 $P_{INT} = I_{DD} \times V_{DD}$, Watts - Chip Internal Power

P_{I/O}= Power Dissipation on Input and Output Pins — User Determined

For most applications $P_{I/O} < P_{INT}$ and can be ignored. An approximate relationship between P_D and T_J (if $P_{I/O}$ is neglected) is:

 $P_{\rm D} = \mathbf{K} \div (\mathbf{T}_{\rm J} + 273^{\circ}C) \quad (2)$

Solving equations 1 and 2 for K gives:

 $K = P_D \times (T_A + 273 \text{ °C}) + \Theta_{JMA} \times P_D^2 (3)$

where K is a constant pertaining to the particular part. K can be determined from equation (3) by measuring P_D (at equilibrium) for a known T_A . Using this value of K, the values of P_D and T_J can be obtained by solving equations (1) and (2) iteratively for any value of T_A .

7.3 DC Electrical Specifications

Table 9. DC Electrical Specifications¹

| Characteristic | Symbol | Min | Typical | Max | Unit |
|---|--------------------|---------------------------------|---------|---------------------------------|------|
| Core Supply Voltage | V _{DD} | 1.4 | | 1.6 | V |
| Pad Supply Voltage | OV _{DD} | 3.0 | _ | 3.6 | V |
| PLL Supply Voltage | V _{DDPLL} | 3.0 | _ | 3.6 | V |
| Input High Voltage | V _{IH} | $0.7 \times OV_{DD}$ | _ | 3.65 | V |
| Input Low Voltage | V _{IL} | V _{SS} – 0.3 | | $0.35\times\text{OV}_\text{DD}$ | V |
| Input Hysteresis | V _{HYS} | $0.06\times\text{OV}_\text{DD}$ | _ | — | mV |
| Input Leakage Current $V_{in} = V_{DD}$ or V_{SS} , Input-only pins | l _{in} | -1.0 | _ | 1.0 | μΑ |
| High Impedance (Off-State) Leakage Current $V_{in} = V_{DD}$ or V_{SS} , All input/output and output pins | I _{OZ} | -1.0 | _ | 1.0 | μΑ |
| Output High Voltage (All input/output and all output pins) $I_{OH} = -5.0 \text{ mA}$ | V _{OH} | OV _{DD} - 0.5 | _ | _ | V |
| Output Low Voltage (All input/output and all output pins) $I_{OL} = 5.0 \text{mA}$ | V _{OL} | — | _ | 0.5 | V |
| Weak Internal Pull Up Device Current, tested at V _{IL} Max. ² | I _{APU} | -10 | _ | - 130 | μA |
| Input Capacitance ³ All input-only pins All input/output (three-state) pins | C _{in} | | _ | 7 7 | pF |

| Characteristic | Symbol | Min | Typical | Max | Unit |
|---|------------------|-------------|------------|-----------|----------|
| Load Capacitance ⁴ Low drive strength High drive strength | CL | | | 25 50 | pF pF |
| Core Operating Supply Current ⁵ Master Mode | I _{DD} | _ | 135 | 150 | mA |
| Pad Operating Supply Current Master Mode Low Power Modes | OI _{DD} | | 100 TBD | | mA μA |
| DC Injection Current ^{3, 6, 7, 8} $V_{NEGCLAMP} = V_{SS} - 0.3 V$, $V_{POSCLAMP} = V_{DD} + 0.3$ Single Pin Limit Total processor Limit, Includes sum of all stressed pins | I _{IC} | -1.0 -10 | | 1.0 10 | mA mA |

Table 9. DC Electrical Specifications¹ (continued)

¹ Refer to Table 10 for additional PLL specifications.

² Refer to the MCF5271 signals section for pins having weak internal pull-up devices.

³ This parameter is characterized before qualification rather than 100% tested.

⁴ pF load ratings are based on DC loading and are provided as an indication of driver strength. High speed interfaces require transmission line analysis to determine proper drive strength and termination. See <u>High Speed Signal Propagation:</u> <u>Advanced Black Magic</u> by Howard W. Johnson for design guidelines.

⁵ Current measured at maximum system clock frequency, all modules active, and default drive strength with matching load.

⁶ All functional non-supply pins are internally clamped to V_{SS} and their respective V_{DD}.

⁷ Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive and negative clamp voltages, then use the larger of the two values.

⁸ Power supply must maintain regulation within operating V_{DD} range during instantaneous and operating maximum current conditions. If positive injection current ($V_{in} > V_{DD}$) is greater than I_{DD} , the injection current may flow out of V_{DD} and could result in external power supply going out of regulation. Insure external V_{DD} load will shunt current greater than maximum injection current. This will be the greatest risk when the processor is not consuming power. Examples are: if no system clock is present, or if clock rate is very low which would reduce overall power consumption. Also, at power-up, system clock is not present during the power-up sequence until the PLL has attained lock.

7.4 Oscillator and PLLMRFM Electrical Characteristics

Table 10. HiP7 PLLMRFM Electrical Specifications¹

| Num | Characteristic | Symbol | Min. Value | Max. Value | Unit |
|-----|---|--|----------------------------|-----------------|-------------------|
| 1 | PLL Reference Frequency Range Crystal reference External reference 1:1 mode (NOTE: f _{sys/2} = 2 × f _{ref_1:1}) | f _{ref_crystal} f _{ref_ext} f _{ref_1:1} | 8 8 24 | 25 25 75 | MHz |
| 2 | Core frequency CLKOUT Frequency ² External reference On-Chip PLL Frequency | f _{sys} f _{sys/2} | 0 f _{ref} ÷ 32 | 150 75 75 | MHz MHz MHz |
| 3 | Loss of Reference Frequency ^{3, 5} | f _{LOR} | 100 | 1000 | kHz |
| 4 | Self Clocked Mode Frequency ^{4, 5} | f _{SCM} | 10.25 | 15.25 | MHz |
| 5 | Crystal Start-up Time ^{5, 6} | t _{cst} | | 10 | ms |

| Num | Characteristic | Symbol | Min. Value | Max. Value | Unit |
|-----|---|---------------------|---------------|---------------|----------------------|
| 6 | XTAL Load Capacitance ⁵ | | 5 | 30 | pF |
| 7 | PLL Lock Time ^{5, 7,13} | t _{lpll} | — | 750 | μS |
| 8 | Power-up To Lock Time ^{5, 6,8} With Crystal Reference (includes 5 time) Without Crystal Reference ⁹ | t _{lplk} | | 11 750 | ms μs |
| 9 | 1:1 Mode Clock Skew (between CLKOUT and EXTAL) ¹⁰ | t _{skew} | -1 | 1 | ns |
| 10 | Duty Cycle of reference ⁵ | t _{dc} | 40 | 60 | % |
| 11 | Frequency un-LOCK Range | f _{UL} | -3.8 | 4.1 | % f _{sys/2} |
| 12 | Frequency LOCK Range | f _{LCK} | -1.7 | 2.0 | % f _{sys/2} |
| 13 | CLKOUT Period Jitter, ^{5, 6, 8,11, 12} Measured at f _{sys/2} Max Peak-to-peak Jitter (Clock edge to clock edge) Long Term Jitter (Averaged over 2 ms interval) | C _{jitter} | _ | 5.0 .01 | % f _{sys/2} |
| 14 | Frequency Modulation Range Limit ^{13,14} (f _{sys/2} Max must not be exceeded) | C _{mod} | 0.8 | 2.2 | %f _{sys/2} |
| 15 | ICO Frequency. $f_{ico} = f_{ref} \times 2 \times (MFD+2)^{15}$ | f _{ico} | 48 | 150 | MHz |

Table 10. HiP7 PLLMRFM Electrical Specifications¹ (continued)

¹ All values given are initial design targets and subject to change.

2 All internal registers retain data at 0 Hz.

³ "Loss of Reference Frequency" is the reference frequency detected internally, which transitions the PLL into self clocked mode.

- 4 Self clocked mode frequency is the frequency that the PLL operates at when the reference frequency falls below fLOR with default MFD/RFD settings.
- ⁵ This parameter is guaranteed by characterization before qualification rather than 100% tested.
- ⁶ Proper PC board layout procedures must be followed to achieve specifications.
- 7 This specification applies to the period required for the PLL to relock after changing the MFD frequency control bits in the synthesizer control register (SYNCR).
- 8 Assuming a reference is available at power up, lock time is measured from the time V_{DD} and V_{DDSYN} are valid to RSTOUT negating. If the crystal oscillator is being used as the reference for the PLL, then the crystal start up time must be added to the PLL lock time to determine the total start-up time.
- 9 $t_{ipli} = (64 + 4 + 5 + 5 \tau)$ T_{ref} , where $T_{ref} = 1/F_{ref_crystal} = 1/F_{ref_ext} = 1/F_{ref_1:1}$, and $\tau = 1.57 \times 10^{-6}$ 2(MFD + 2).
- ¹⁰ PLL is operating in 1:1 PLL mode.
- ¹¹ Jitter is the average deviation from the programmed frequency measured over the specified interval at maximum f_{sys/2}. Measurements are made with the device powered by filtered supplies and clocked by a stable external clock signal. Noise injected into the PLL circuitry via V_{DDSYN} and V_{SSSYN} and variation in crystal oscillator frequency increase the Cjitter percentage for a given interval.
- ¹² Values are with frequency modulation disabled. If frequency modulation is enabled, jitter is the sum of Cjitter+Cmod.
- ¹³ Modulation percentage applies over an interval of 10µs, or equivalently the modulation rate is 100KHz. ¹⁴ Modulation rate selected must not result in $f_{svs/2}$ value greater than the $f_{svs/2}$ maximum specified value.
- Modulation range determined by hardware design. ¹⁵ $f_{sys/2} = f_{ico} / (2 * 2^{RFD})$

7.5 External Interface Timing Characteristics

Table 11 lists processor bus input timings.

NOTE

All processor bus timings are synchronous; that is, input setup/hold and output delay with respect to the rising edge of a reference clock. The reference clock is the CLKOUT output.

All other timing relationships can be derived from these values.

| Name | e Characteristic ¹ | | Min | Max | Unit | | | |
|------|---|--------------------|-----|------|------|--|--|--|
| freq | System bus frequency | f _{sys/2} | 50 | 75 | MHz | | | |
| B0 | CLKOUT period | t _{cyc} | | 1/75 | ns | | | |
| | Control Inputs | | | | | | | |
| B1a | Control input valid to CLKOUT high ² | t _{CVCH} | 9 | — | ns | | | |
| B1b | BKPT valid to CLKOUT high ³ | t _{BKVCH} | 9 | — | ns | | | |
| B2a | CLKOUT high to control inputs invalid ² | | 0 | | ns | | | |
| B2b | CLKOUT high to asynchronous control input BKPT invalid ³ | | 0 | — | ns | | | |
| | Data Inputs | | | | | | | |
| B4 | Data input (D[31:0]) valid to CLKOUT high | t _{DIVCH} | 4 | | ns | | | |
| B5 | CLKOUT high to data input (D[31:0]) invalid | t _{CHDII} | 0 | — | ns | | | |

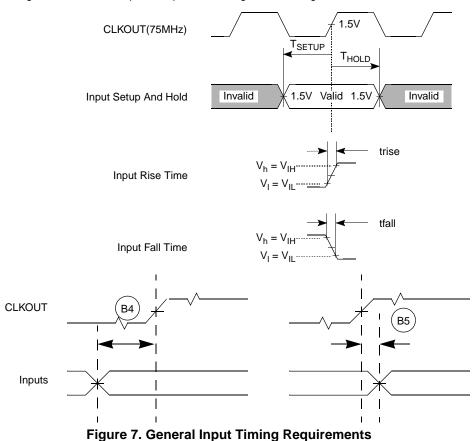
Table 11. Processor Bus Input Timing Specifications

¹ Timing specifications are tested using full drive strength pad configurations in a 50ohm transmission line environment..

 2 TEA and TA pins are being referred to as control inputs.

³ Refer to figure A-19.

Timings listed in Table 11 are shown in Figure 7.



* The timings are also valid for inputs sampled on the negative clock edge.

7.6 **Processor Bus Output Timing Specifications**

Table 12 lists processor bus output timings.

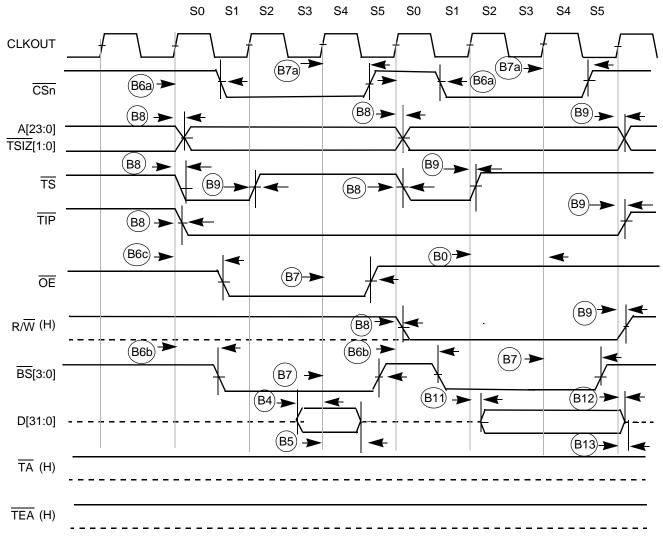
| Table 12. Externa | al Bus Output | Timing S | Specifications |
|-------------------|---------------|----------|----------------|
|-------------------|---------------|----------|----------------|

| Name | Characteristic | Symbol | Min | Max | Unit | | | | |
|------|---|--------------------|--------------------------|------------------------|------|--|--|--|--|
| | Control Outputs | | | | | | | | |
| B6a | CLKOUT high to chip selects valid ¹ | ^t CHC∨ | _ | 0.5t _{CYC} +5 | ns | | | | |
| B6b | CLKOUT high to byte enables (BS[3:0]) valid ² | t _{CHBV} | _ | 0.5t _{CYC} +5 | ns | | | | |
| B6c | CLKOUT high to output enable (\overline{OE}) valid ³ | t _{CHOV} | _ | 0.5t _{CYC} +5 | ns | | | | |
| B7 | CLKOUT high to control output (BS[3:0], OE) invalid | t _{CHCOI} | 0.5t _{CYC} +1.5 | | ns | | | | |
| B7a | CLKOUT high to chip selects invalid | t _{CHCI} | 0.5t _{CYC} +1.5 | — | ns | | | | |

| Name | Characteristic | Symbol | Min | Max | Unit | | | | |
|------|---|--------------------|-----|-----|------|--|--|--|--|
| | Address and Attribute Outputs | | | | | | | | |
| B8 | CLKOUT high to address (A[23:0]) and control (\overline{TS} , TSIZ[1:0], TIP, R/W) valid | t _{CHAV} | _ | 9 | ns | | | | |
| B9 | CLKOUT high to address (A[23:0]) and control (\overline{TS} , TSIZ[1:0], TIP, R/W) invalid | t _{CHAI} | 1.5 | _ | ns | | | | |
| | Data Outputs | | | | | | | | |
| B11 | CLKOUT high to data output (D[31:0]) valid | t _{CHDOV} | _ | 9 | ns | | | | |
| B12 | CLKOUT high to data output (D[31:0]) invalid | t _{CHDOI} | 1.5 | — | ns | | | | |
| B13 | CLKOUT high to data output (D[31:0]) high impedance | t _{CHDOZ} | _ | 9 | ns | | | | |

Table 12. External Bus Output Timing Specifications (continued)

CS transitions after the falling edge of CLKOUT.
 BS transitions after the falling edge of CLKOUT.
 OE transitions after the falling edge of CLKOUT.



Read/write bus timings listed in Table 12 are shown in Figure 8, Figure 9, and Figure 10.

Figure 8. Read/Write (Internally Terminated) SRAM Bus Timing

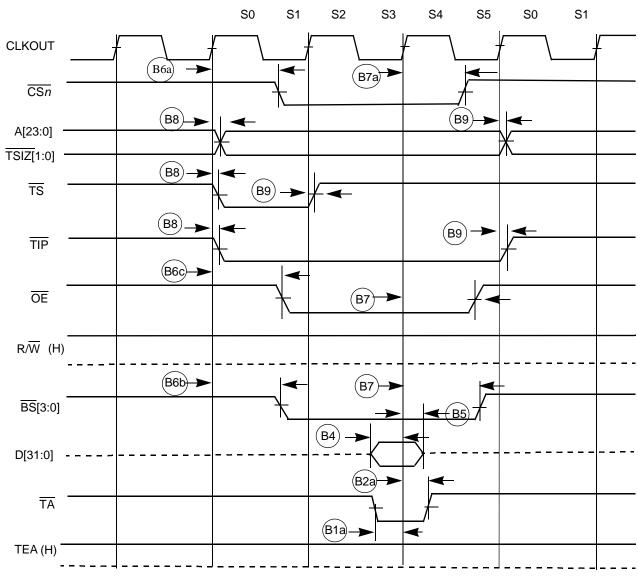


Figure 9 shows a bus cycle terminated by \overline{TA} showing timings listed in Table 12.

Figure 9. SRAM Read Bus Cycle Terminated by TA

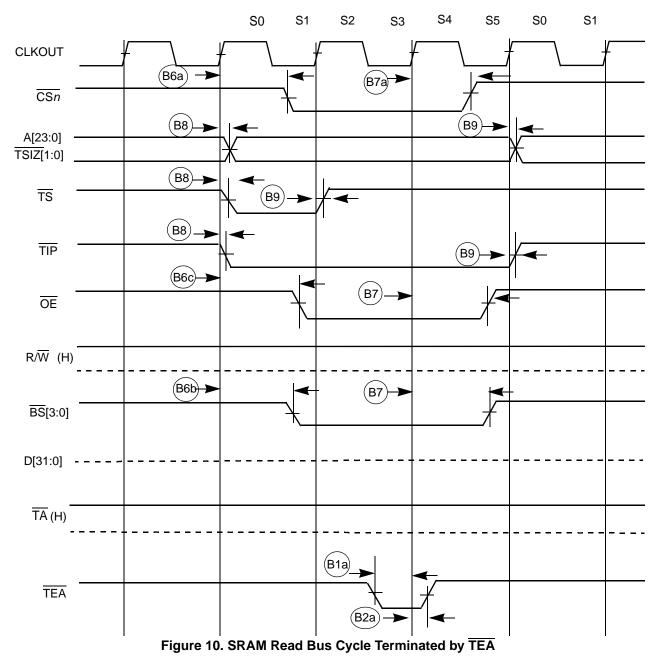
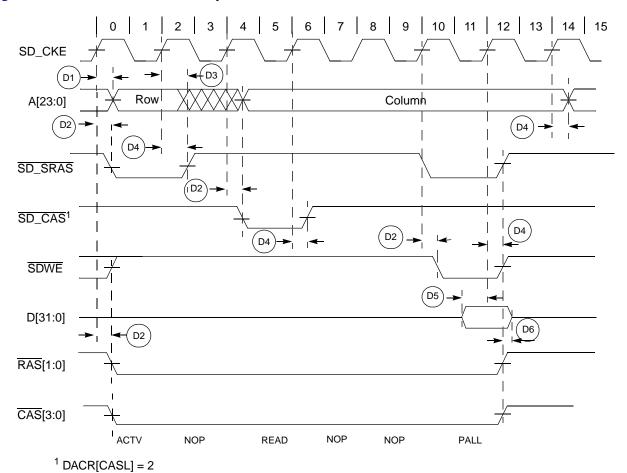


Figure 10 shows an SRAM bus cycle terminated by $\overline{\text{TEA}}$ showing timings listed in Table 12.

Figure 11 shows an SDRAM read cycle.



| Figure | 11. | SDRAM | Read | Cycle |
|--------|-----|-------|------|-------|
|--------|-----|-------|------|-------|

| Table | 13. | SDRAM | Timing |
|-------|-----|-------|--------|
|-------|-----|-------|--------|

| NUM | Characteristic | Symbol | Min | Max | Unit |
|-----------------|--------------------------------------|---------------------|-----|-----|------|
| D1 | CLKOUT high to SDRAM address valid | t _{CHDAV} | _ | 9 | ns |
| D2 | CLKOUT high to SDRAM control valid | t _{CHDCV} | _ | 9 | ns |
| D3 | CLKOUT high to SDRAM address invalid | t _{CHDAI} | 1.5 | — | ns |
| D4 | CLKOUT high to SDRAM control invalid | t _{CHDCI} | 1.5 | — | ns |
| D5 | SDRAM data valid to CLKOUT high | t _{DDVCH} | 4 | — | ns |
| D6 | CLKOUT high to SDRAM data invalid | t _{CHDDI} | 1.5 | — | ns |
| D7 ¹ | CLKOUT high to SDRAM data valid | t _{CHDDVW} | _ | 9 | ns |
| D8 ¹ | CLKOUT high to SDRAM data invalid | t _{CHDDIW} | 1.5 | _ | ns |

¹ D7 and D8 are for write cycles only.

Figure 12 shows an SDRAM write cycle.

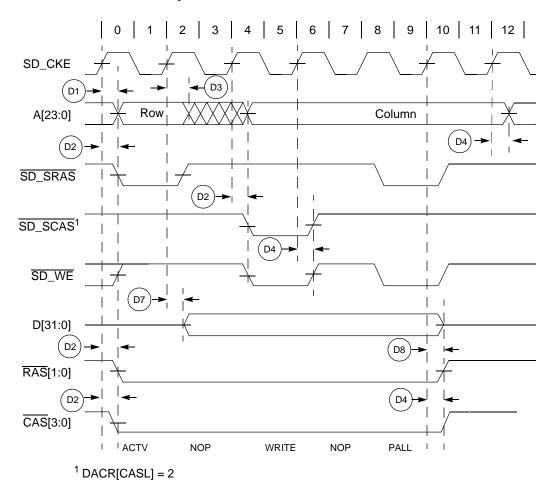


Figure 12. SDRAM Write Cycle

7.7 General Purpose I/O Timing

Table 14. GPIO Timing¹

| NUM | Characteristic | Symbol | Min | Max | Unit |
|-----|------------------------------------|--------------------|-----|-----|------|
| G1 | CLKOUT High to GPIO Output Valid | t _{CHPOV} | _ | 10 | ns |
| G2 | CLKOUT High to GPIO Output Invalid | t _{CHPOI} | 1.5 | _ | ns |
| G3 | GPIO Input Valid to CLKOUT High | t _{PVCH} | 9 | _ | ns |
| G4 | CLKOUT High to GPIO Input Invalid | t _{CHPI} | 1.5 | — | ns |

¹ GPIO pins include: INT, UART, Timer, DREQn and DACKn pins.

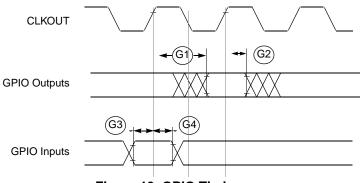


Figure 13. GPIO Timing

7.8 Reset and Configuration Override Timing

Table 15. Reset and Configuration Override Timing $(V_{DD} = 2.7 \text{ to } 3.6 \text{ V}, \text{ V}_{SS} = 0 \text{ V}, \text{ T}_{A} = \text{T}_{L} \text{ to } \text{T}_{H})^{1}$

| NUM | Characteristic | Symbol | Min | Max | Unit |
|-----|---|--------------------|-----|-----|------------------|
| R1 | RESET Input valid to CLKOUT High | t _{RVCH} | 9 | — | ns |
| R2 | CLKOUT High to RESET Input invalid | t _{CHRI} | 1.5 | — | ns |
| R3 | RESET Input valid Time ² | t _{RIVT} | 5 | — | t _{CYC} |
| R4 | CLKOUT High to RSTOUT Valid | t _{CHROV} | — | 10 | ns |
| R5 | RSTOUT valid to Config. Overrides valid | t _{ROVCV} | 0 | — | ns |
| R6 | Configuration Override Setup Time to RSTOUT invalid | t _{COS} | 20 | — | t _{CYC} |
| R7 | Configuration Override Hold Time after RSTOUT invalid | t _{COH} | 0 | — | ns |
| R8 | RSTOUT invalid to Configuration Override High Impedance | t _{ROICZ} | — | 1 | t _{CYC} |

¹ All AC timing is shown with respect to 50% V_{DD} levels unless otherwise noted.

² During low power STOP, the synchronizers for the RESET input are bypassed and RESET is asserted asynchronously to the system. Thus, RESET must be held a minimum of 100 ns.

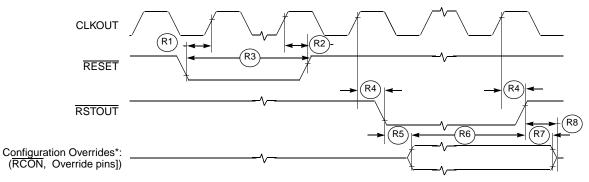


Figure 14. RESET and Configuration Override Timing

Refer to the chip configuration module (CCM) chapter in the device's reference manual for more information.

7.9 I²C Input/Output Timing Specifications

Table 16 lists specifications for the I^2C input timing parameters shown in Figure 15.

| Num | Characteristic | Min | Max | Units |
|-----|---|-----|-----|------------------|
| 11 | Start condition hold time | 2 | — | t _{cyc} |
| 12 | Clock low period | 8 | — | t _{cyc} |
| 13 | I2C_SCL/I2C_SDA rise time ($V_{IL} = 0.5 \text{ V to } V_{IH} = 2.4 \text{ V}$) | — | 1 | ms |
| 14 | Data hold time | 0 | — | ns |
| 15 | I2C_SCL/I2C_SDA fall time ($V_{IH} = 2.4$ V to $V_{IL} = 0.5$ V) | — | 1 | ms |
| 16 | Clock high time | 4 | — | t _{cyc} |
| 17 | Data setup time | 0 | — | ns |
| 18 | Start condition setup time (for repeated start condition only) | 2 | — | t _{cyc} |
| 19 | Stop condition setup time | 2 | — | t _{cyc} |

Table 16. I²C Input Timing Specifications between I2C_SCL and I2C_SDA

Table 17 lists specifications for the I^2C output timing parameters shown in Figure 15.

| Table 17. I ² C Output Timing | Specifications between I2C | _SCL and I2C_SDA |
|--|----------------------------|------------------|
|--|----------------------------|------------------|

| Num | Characteristic | Min | Max | Units |
|-----------------|--|-----|-----|------------------|
| 11 ¹ | Start condition hold time | 6 | _ | t _{cyc} |
| 12 ¹ | Clock low period | 10 | — | t _{cyc} |
| 13 ² | I2C_SCL/I2C_SDA rise time (V _{IL} = 0.5 V to V _{IH} = 2.4 V) | _ | — | μs |
| I4 ¹ | Data hold time | 7 | — | t _{cyc} |
| I5 ³ | I2C_SCL/I2C_SDA fall time (V_{IH} = 2.4 V to V_{IL} = 0.5 V) | _ | 3 | ns |
| I6 ¹ | Clock high time | 10 | — | t _{cyc} |
| 17 ¹ | Data setup time | 2 | — | t _{cyc} |
| 18 ¹ | Start condition setup time (for repeated start condition only) | 20 | — | t _{cyc} |
| 19 ¹ | Stop condition setup time | 10 | — | t _{cyc} |

Note: Output numbers depend on the value programmed into the IFDR; an IFDR programmed with the maximum frequency (IFDR = 0x20) results in minimum output timings as shown in Table 17. The I^2C interface is designed to scale the actual data transition time to move it to the middle of the I2C_SCL low period. The actual position is affected by the prescale and division values programmed into the IFDR; however, the numbers given in Table 17 are minimum values.

² Because I2C_SCL and I2C_SDA are open-collector-type outputs, which the processor can only actively drive low, the time I2C_SCL or I2C_SDA take to reach a high level depends on external signal capacitance and pull-up resistor values.

³ Specified at a nominal 50-pF load.

Figure 15 shows timing for the values in Table 16 and Table 17.

1

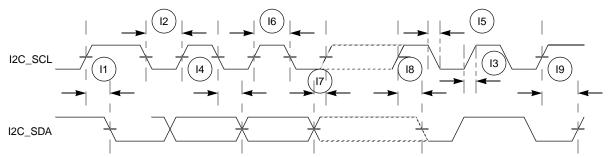


Figure 15. I²C Input/Output Timings

7.10 Fast Ethernet AC Timing Specifications

MII signals use TTL signal levels compatible with devices operating at either 5.0 V or 3.3 V.

7.10.1 MII Receive Signal Timing (ERXD[3:0], ERXDV, ERXER, and ERXCLK)

The receiver functions correctly up to a ERXCLK maximum frequency of 25 MHz +1%. The processor clock frequency must exceed twice the ERXCLK frequency.

Table 18 lists MII receive channel timings.

Table 18. MII Receive Signal Timing

| Num | Characteristic | Min | Max | Unit |
|-----|---|-----|-----|---------------|
| M1 | ERXD[3:0], ERXDV, ERXER to ERXCLK setup | 5 | _ | ns |
| M2 | ERXCLK to ERXD[3:0], ERXDV, ERXER hold | 5 | _ | ns |
| M3 | ERXCLK pulse width high | 35% | 65% | ERXCLK period |
| M4 | ERXCLK pulse width low | 35% | 65% | ERXCLK period |

Figure 16 shows MII receive signal timings listed in Table 18.

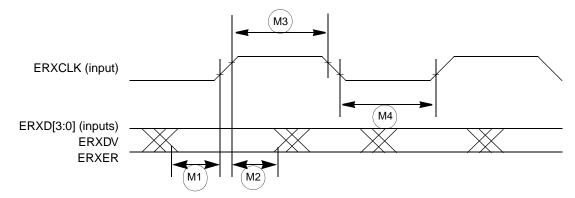


Figure 16. MII Receive Signal Timing Diagram

7.10.2 MII Transmit Signal Timing (ETXD[3:0], ETXEN, ETXER, ETXCLK)

 Table 19 lists MII transmit channel timings.

The transmitter functions correctly up to a ETXCLK maximum frequency of 25 MHz +1%. The processor clock frequency must exceed twice the ETXCLK frequency.

| Num | Characteristic | Min | Max | Unit |
|-----|---|-----|-----|---------------|
| M5 | ETXCLK to ETXD[3:0], ETXEN, ETXER invalid | 5 | _ | ns |
| M6 | ETXCLK to ETXD[3:0], ETXEN, ETXER valid | — | 25 | ns |
| M7 | ETXCLK pulse width high | 35% | 65% | ETXCLK period |
| M8 | ETXCLK pulse width low | 35% | 65% | ETXCLK period |

Figure 17 shows MII transmit signal timings listed in Table 19.

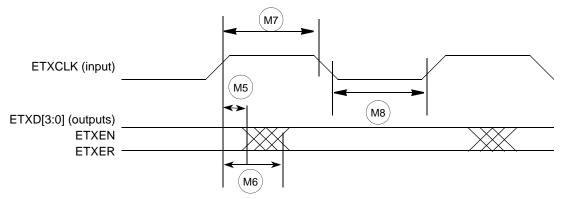


Figure 17. MII Transmit Signal Timing Diagram

7.10.3 MII Async Inputs Signal Timing (ECRS and ECOL)

Table 20 lists MII asynchronous inputs signal timing.

Table 20. MII Async Inputs Signal Timing

| Ī | Num | Characteristic | Min | Мах | Unit |
|---|-----|--------------------------------|-----|-----|---------------|
| Ī | M9 | ECRS, ECOL minimum pulse width | 1.5 | _ | ETXCLK period |

Figure 18 shows MII asynchronous input timings listed in Table 20.

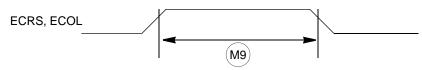


Figure 18. MII Async Inputs Timing Diagram

7.10.4 MII Serial Management Channel Timing (EMDIO and EMDC)

Table 21 lists MII serial management channel timings. The FEC functions correctly with a maximum MDC frequency of 2.5 MHz.

| Num | Characteristic | Min | Max | Unit |
|-----|---|-----|-----|------------|
| M10 | EMDC falling edge to EMDIO output invalid (minimum propagation delay) | 0 | _ | ns |
| M11 | EMDC falling edge to EMDIO output valid (max prop delay) | — | 25 | ns |
| M12 | EMDIO (input) to EMDC rising edge setup | 10 | _ | ns |
| M13 | EMDIO (input) to EMDC rising edge hold | 0 | | ns |
| M14 | EMDC pulse width high | 40% | 60% | MDC period |
| M15 | EMDC pulse width low | 40% | 60% | MDC period |

Figure 19 shows MII serial management channel timings listed in Table 21.

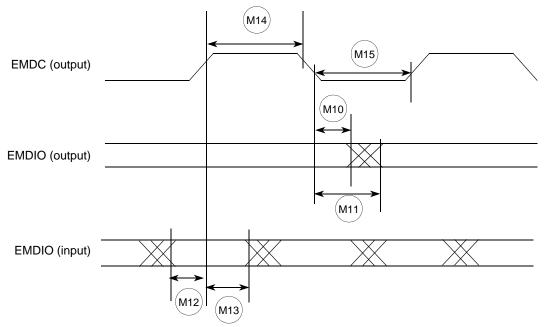


Figure 19. MII Serial Management Channel Timing Diagram

7.11 32-Bit Timer Module AC Timing Specifications

Table 22 lists timer module AC timings.

| Name | Characteristic | 0–66 MHz | | Unit |
|------|---|----------|-----|------------------|
| Nume | | Min | Max | onit |
| T1 | DT0IN / DT1IN / DT2IN / DT3IN cycle time | 3 | _ | t _{CYC} |
| T2 | DT0IN / DT1IN / DT2IN / DT3IN pulse width | 1 | _ | t _{CYC} |

7.12 **QSPI Electrical Specifications**

Table 23 lists QSPI timings.

| Name | Characteristic | Min | Max | Unit |
|------|---|-----|-----|------|
| QS1 | QSPI_CS[1:0] to QSPI_CLK | 1 | 510 | tcyc |
| QS2 | QSPI_CLK high to QSPI_DOUT valid. | _ | 10 | ns |
| QS3 | QSPI_CLK high to QSPI_DOUT invalid. (Output hold) | 2 | _ | ns |
| QS4 | QSPI_DIN to QSPI_CLK (Input setup) | 9 | _ | ns |
| QS5 | QSPI_DIN to QSPI_CLK (Input hold) | 9 | _ | ns |

The values in Table 23 correspond to Figure 20.

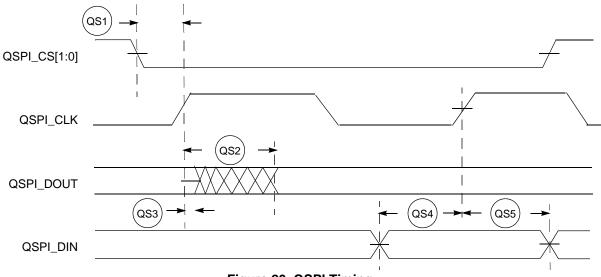


Figure 20. QSPI Timing

JTAG and Boundary Scan Timing 7.13

Table 24. JTAG and Boundary Scan Timing

| LK Frequency of Operation LK Cycle Period LK Clock Pulse Width LK Rise and Fall Times undary Scan Input Data Setup Time to TCLK Rise | fJCYC tJCYC tJCW tJCRF tBSDST | DC 4 26 0 | 1/4 — — 3 | f _{sys/2} t _{CYC} ns |
|--|--|--|---|--|
| LK Clock Pulse Width LK Rise and Fall Times undary Scan Input Data Setup Time to TCLK Rise | t _{JCW} t _{JCRF} | 26 | | |
| LK Rise and Fall Times undary Scan Input Data Setup Time to TCLK Rise | t _{JCRF} | | | ns |
| undary Scan Input Data Setup Time to TCLK Rise | | 0 | 3 | |
| | t _{BSDST} | | | ns |
| | 00001 | 4 | — | ns |
| undary Scan Input Data Hold Time after TCLK Rise | t _{BSDHT} | 26 | — | ns |
| LK Low to Boundary Scan Output Data Valid | t _{BSDV} | 0 | 33 | ns |
| LK Low to Boundary Scan Output High Z | t _{BSDZ} | 0 | 33 | ns |
| S, TDI Input Data Setup Time to TCLK Rise | t _{TAPBST} | 4 | — | ns |
| S, TDI Input Data Hold Time after TCLK Rise | t _{TAPBHT} | 10 | — | ns |
| LK Low to TDO Data Valid | t _{TDODV} | 0 | 26 | ns |
| LK Low to TDO High Z | t _{TDODZ} | 0 | 8 | ns |
| ST Assert Time | t _{TRSTAT} | 100 | — | ns |
| ST Setup Time (Negation) to TCLK High | t _{TRSTST} | 10 | — | ns |
| | G, TDI Input Data Setup Time to TCLK Rise G, TDI Input Data Hold Time after TCLK Rise K Low to TDO Data Valid K Low to TDO High Z TAssert Time | S, TDI Input Data Setup Time to TCLK Rise t _{TAPBST} S, TDI Input Data Hold Time after TCLK Rise t _{TAPBHT} K Low to TDO Data Valid t _{TDODV} K Low to TDO High Z t _{TDODZ} T Assert Time t _{TRSTAT} T Setup Time (Negation) to TCLK High t _{TRSTST} | S, TDI Input Data Setup Time to TCLK Riset_TAPBST4S, TDI Input Data Hold Time after TCLK Riset_TAPBHT10LK Low to TDO Data Validt_TDODV0LK Low to TDO High Zt_TDODZ0ST Assert Timet_TRSTAT100ST Setup Time (Negation) to TCLK Hight_TRSTST10 | S, TDI Input Data Setup Time to TCLK Rise t_TAPBST 4 S, TDI Input Data Hold Time after TCLK Rise t_TAPBHT 10 K Low to TDO Data Valid t_TDODV 0 26 K Low to TDO High Z t_TDODZ 0 8 T Assert Time t_TRSTAT 100 |

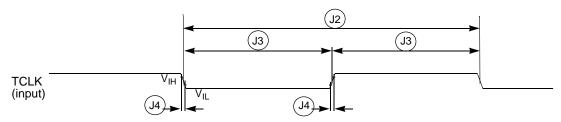
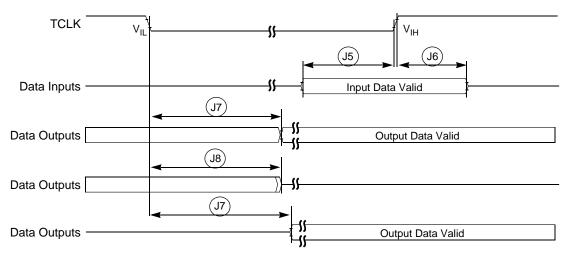
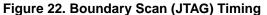
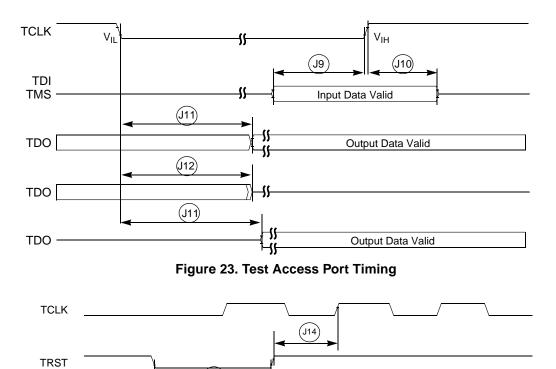


Figure 21. Test Clock Input Timing









(J13)

7.14 Debug AC Timing Specifications

Table 25 lists specifications for the debug AC timing parameters shown in Figure 26.

| Num | Characteristic | 150 MHz | | Units | |
|--|---|---------|-----|------------------|--|
| Nulli | | Min | Max | Units | |
| DE0 | PSTCLK cycle time | — | 0.5 | t _{cyc} | |
| DE1 | PST valid to PSTCLK high | 4 | — | ns | |
| DE2 | PSTCLK high to PST invalid | 1.5 | — | ns | |
| DE3 | DSCLK cycle time | 5 | | t _{cyc} | |
| DE4 | DSI valid to DSCLK high | 1 | — | t _{cyc} | |
| DE5 ¹ | DSCLK high to DSO invalid | 4 | — | t _{cyc} | |
| DE6 | BKPT input data setup time to CLKOUT rise | 4 | | ns | |
| DE7 | CLKOUT high to BKPT high Z | 0 | 10 | ns | |
| ¹ DSCLK and DSI are synchronized internally. D4 is measured from the synchronized DSCLK | | | | | |

Table 25. Debug AC Timing Specification

DSCLK and DSI are synchronized internally. D4 is measured from the synchronized DSCLK input relative to the rising edge of CLKOUT.

Figure 25 shows real-time trace timing for the values in Table 25.

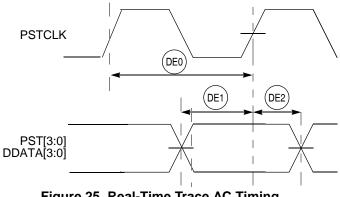


Figure 25. Real-Time Trace AC Timing

Figure 26 shows BDM serial port AC timing for the values in Table 25.

Documentation

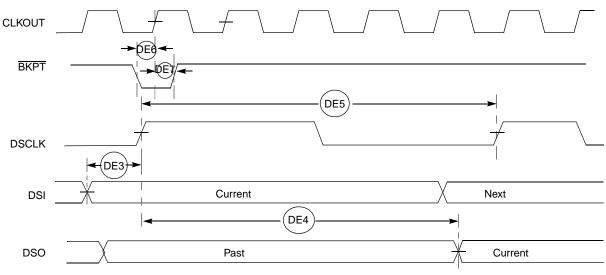


Figure 26. BDM Serial Port AC Timing

8 Documentation

Documentation regarding the MCF5271 and their development support tools is available from a local Freescale distributor, a Freescale semiconductor sales office, the Freescale Literature Distribution Center, or through the Freescale web address at http://www.freescale.com/coldfire.

9 Document Revision History

The below table provides a revision history for this document.

| Rev. No. | Substantive Change(s) | |
|----------|--|--|
| 0 | Initial release | |
| 1 | Fixed several clock values. Updated Signal List table | |
| 1.1 | Removed duplicate information in the module description sections. The information is all in the Signals Description Table. | |
| 1.2 | Removed detailed signal description section. This information can be found in the MCF5271RM Chapter 2. Removed detailed feature list. This information can be found in the MCF5271RM Chapter 1. Changed instances of Motorola to Freescale Added values for 'Maximum operating junction temperature' in Table 8. Added typical values for 'Core operating supply current (master mode)' in Table 9. Added typical values for 'Pad operating supply current (master mode)' in Table 9. Removed unnecessary PLL specifications, #6-9, in Table 10. | |

Document Revision History

| Rev. No. | Substantive Change(s) |
|----------|--|
| 1.3 | Device is now available in 150 MHz versions. Updated specs where necessary to reflect this improvement. Added 2 new part numbers to Table 6: MCF5270CVM150 and MCF5271CVM150. Removed features list. This information can be found in the MCF5271RM. Removed SDRAM address multiplexing section. This information can be found in the MCF5271RM. |
| 1.4 | Added Section 5.2.1, "Supply Voltage Sequencing and Separation Cautions." Updated 196MAPBGA package dimensions, Figure 4. |
| 2 | Table 2: Changed SD_CKE pin location from 139 to "—" for the 160QFP device. Table 2: Changed QSPI_CS1 pin location from "—" to 139 for the 160QFP device. Table 2: Changed DT3IN pin's alternate 2 function from "—" to QSPI_CS2. Table 2: Changed DT3OUT pin's alternate 2 function from "—" to QSPI_CS3. Figure 5: Changed pin 139 label from "SD_CKE/QSPI_CS1" to "QSPI_CS1/SD_CKE". Removed second sentence from Section 7.10.1, "MII Receive Signal Timing (ERXD[3:0], ETXEN, ETXER, ETXCLK)," regarding no minimum frequency requirement for TXCLK. Removed third and fourth paragraphs from Section 7.10.2, "MII Transmit Signal Timing (ETXD[3:0], ETXEN, ETXEN, ETXER, ETXCLK)," as this feature is not supported on this device. |
| 3 | Section 5.2.1, "Supply Voltage Sequencing and Separation Cautions" changed PLLV_{DD} to V_{DDPLL} to match rest of document. Section 5.2.1, "Supply Voltage Sequencing and Separation Cautions" Changed V_{DDPLL} voltage level from 1.5V to 3.3V throughout section. Section 5.2.1.1, "Power Up Sequence" first bullet, changed "Use 1 µs" to "Use 1 ms". Corrected position of spec D5 in Figure 11. Figure 3: Corrected M4 ball location from DATA5 to DATA6, changed DATA<i>n</i> labels to D<i>n</i> for consistency Table 14: Added DACK<i>n</i> and DREQ<i>n</i> to footnote. Table 9, added PLL supply voltage row |
| 4 | Added part number MCF5270CAB100 in Table 6 |

Table 26. MCF5271EC Revision History (continued)

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